

Prof. EMRE COŞKUN

Personal Information

Office Phone: [+90 286 218 0018](tel:+902862180018) Extension: 22220

Email: ecoskun@comu.edu.tr

Web: <https://avesis.comu.edu.tr/ecoskun>

International Researcher IDs

ORCID: 0000-0002-6820-3889

Yoksis Researcher ID: 124266

Education Information

2012 - 2014	Post Doctorate, Middle East Technical University, Fizik, Turkey
2005 - 2012	Doctorate, Canakkale Onsekiz Mart University, Fen Fakültesi, Fizik, Turkey
2003 - 2005	Postgraduate, Gebze Yüksek Teknoloji Enstitüsü, Fen Bilimleri Enstitüsü, Fizik, Turkey
1996 - 2003	Undergraduate, Hacettepe University, Mühendislik Fakültesi, Fizik Mühendisliği, Turkey

Foreign Languages

English, C1 Advanced

Dissertations

2012	Determination of the optical properties of thin films by integral transform methods, Canakkale Onsekiz Mart University, Fen Fakültesi, Fizik, Doctorate
2005	Investigation of TlGaSe ₂ crystal by thermally stimulated current method, Gebze Yüksek Teknoloji Enstitüsü, Postgraduate

Research Areas

Physics, Condensed Matter 1: Structural, Mechanical and Thermal Properties, Surfaces, Interfaces, Thin Films and Nanosystems, Intensive Article 2: Electronic Structure, Electric, Magnetic and Optical Properties, Electrical properties of electronic structures, interfaces, thin films and low-dimensional structures, Optical Properties, Spectroscopy of Matter, Natural Sciences

Academic Titles / Tasks

2019 - Continues	Associate Professor, Canakkale Onsekiz Mart University, Fen Fakültesi, Fizik
2005 - 2019	Research Assistant PhD, Canakkale Onsekiz Mart University, Fen Fakültesi, Fizik

Courses

2020 - 2021	Physics II, Undergraduate
2019 - 2020	Physics II, Undergraduate
2020 - 2021	Physics I, Undergraduate
2019 - 2020	Biophysics, Undergraduate
2019 - 2020	PHYSICS I, Undergraduate

Published journal articles indexed by SCI, SSCI, and AHCI

- I. **A new method to determine the continuous refractive index of an absorbing film by Generalized Stockwell Transform**
COŞKUN E., Emir C., Selamet S., PARLAK M., ÖZDER S.
Optics and Laser Technology, vol.167, 2023 (SCI-Expanded)
- II. **Nanowire geometry effects on devices and transport mechanisms: SnS₂/SiNW heterojunction**
Coşkun E., Emir C., Terlemezoglu M., Parlak M.
JOURNAL OF MATERIALS SCIENCE, vol.58, pp.15132-15143, 2023 (SCI-Expanded)
- III. **Improvement of electrical characteristics of SnSe/Si heterostructure by integration of Si nanowires**
Coşkun E., Gullu H. H., Emir C., Parlak M.
PHYSICA B-CONDENSED MATTER, vol.604, 2021 (SCI-Expanded)
- IV. **Simultaneous determination of the thickness and refractive index dispersion of dielectric films by the Paul wavelet transform**
ÖZCAN S., COŞKUN E., KOCAHAN YILMAZ Ö., ÖZDER S.
THIN SOLID FILMS, vol.692, 2019 (SCI-Expanded)
- V. **FABRICATION AND CHARACTERIZATION OF TiO₂ THIN FILM FOR DEVICE APPLICATIONS**
Hosseini A., Gullu H. H., Coskun E., Parlak M., Ercelebi C.
SURFACE REVIEW AND LETTERS, vol.26, no.6, 2019 (SCI-Expanded)
- VI. **Effects of Si nanowire on the device properties of n-ZnSe/p-Si heterostructure**
Coskun E., Gullu H. H., Colakoglu T., Emir C., Bozdogan E., Parlak M.
JOURNAL OF MATERIALS SCIENCE-MATERIALS IN ELECTRONICS, vol.30, no.5, pp.4760-4765, 2019 (SCI-Expanded)
- VII. **The zero order generalized Morse wavelet method to determine the refractive index and extinction coefficient dispersions of an absorbing film**
KOCAHAN YILMAZ Ö., COŞKUN E., Tiryaki E., ÖZDER S.
THIN SOLID FILMS, vol.673, pp.72-77, 2019 (SCI-Expanded)
- VIII. **Optical band gap and dispersion of optical constants of Cu-Ga-S thin films**
Isik M., Gullu H. H., Coskun E., HASANLI N.
OPTIK, vol.186, pp.147-154, 2019 (SCI-Expanded)
- IX. **Determination of phase from the ridge of CWT using generalized Morse wavelet**
KOCAHAN YILMAZ Ö., Tiryaki E., COŞKUN E., ÖZDER S.
MEASUREMENT SCIENCE AND TECHNOLOGY, vol.29, no.3, 2018 (SCI-Expanded)
- X. **The generalized Morse wavelet method to determine refractive index dispersion of dielectric films**
KOCAHAN YILMAZ Ö., ÖZCAN S., COŞKUN E., ÖZDER S.
MEASUREMENT SCIENCE AND TECHNOLOGY, vol.28, no.4, 2017 (SCI-Expanded)
- XI. **Investigations of thermal annealing role on the optical properties of Zn-In-Se thin films**
Gullu H. H., COŞKUN E., Parlak M.
OPTIK, vol.144, pp.603-612, 2017 (SCI-Expanded)
- XII. **Generalized Morse wavelet for the determination of the birefringence of a liquid crystal cell**
KOCAHAN YILMAZ Ö., COŞKUN E., ÖZDER S.
MEASUREMENT SCIENCE AND TECHNOLOGY, vol.26, no.8, 2015 (SCI-Expanded)
- XIII. **Device behavior of an In/p-Ag(Ga,In)Te-2/n-Si/Ag heterojunction diode**
COŞKUN E., Gullu H. H., CANDAN İ., Bayraklı O., PARLAK M., Ercelebi C.
MATERIALS SCIENCE IN SEMICONDUCTOR PROCESSING, vol.34, pp.138-145, 2015 (SCI-Expanded)
- XIV. **Study on the Structural and Electrical Properties of Sequentially Deposited Ag-Ga-In-Te Thin Films**
COŞKUN E., Gullu H. H., Parlak M., Ercelebi C.
JOURNAL OF LOW TEMPERATURE PHYSICS, vol.178, pp.162-173, 2015 (SCI-Expanded)
- XV. **Investigation of structural and optical parameters of Cu-Ag-In-Se thin films deposited by thermal**

evaporation method

Gullu H. H., CANDAN İ., COŞKUN E., Parlak M.

OPTIK, vol.126, no.18, pp.1578-1583, 2015 (SCI-Expanded)

- XVI. **Device application of AgGa0.5In0.5Se2 thin films deposited by thermal sequential stacked layer method**
COŞKUN E., Gullu H. H., Parlak M.
MATERIALS RESEARCH EXPRESS, vol.1, no.4, 2014 (SCI-Expanded)
- XVII. **Characterization of Co-evaporated Cu-Ag-In-Se Thin Films**
Gullu H. H., COŞKUN E., Parlak M.
BRAZILIAN JOURNAL OF PHYSICS, vol.44, no.6, pp.719-725, 2014 (SCI-Expanded)
- XVIII. **Generalized Morse wavelets for the phase evaluation of projected fringe pattern**
KOCAHAN YILMAZ Ö., COŞKUN E., ÖZDER S.
MEASUREMENT SCIENCE AND TECHNOLOGY, vol.25, no.10, 2014 (SCI-Expanded)
- XIX. **The Paul wavelet algorithm: an alternative approach to calculate the refractive index dispersion of a dielectric film from transmittance spectrum**
COŞKUN E., ÖZDER S., Tiryaki E.
APPLIED PHYSICS B-LASERS AND OPTICS, vol.113, no.2, pp.243-250, 2013 (SCI-Expanded)
- XX. **Structural and optical properties of Zn-In-Te thin films deposited by thermal evaporation technique**
Gullu H. H., Bayraklı O., CANDAN İ., COŞKUN E., Parlak M.
JOURNAL OF ALLOYS AND COMPOUNDS, vol.566, pp.83-89, 2013 (SCI-Expanded)
- XXI. **Paul wavelet algorithm for the determination of birefringence dispersion of a liquid crystal cell**
COŞKUN E., ÖZDER S.
JOURNAL OF THE OPTICAL SOCIETY OF AMERICA B-OPTICAL PHYSICS, vol.28, no.12, pp.2974-2978, 2011 (SCI-Expanded)
- XXII. **Determination of the refractive index of a dielectric film continuously by the generalized S-transform**
COŞKUN E., SEL K., ÖZDER S.
OPTICS LETTERS, vol.35, no.6, pp.841-843, 2010 (SCI-Expanded)
- XXIII. **Refractive index and extinction coefficient determination of an absorbing thin film by using the continuous wavelet transform method**
COŞKUN E., SEL K., ÖZDER S., KURT M.
APPLIED OPTICS, vol.47, no.27, pp.4888-4894, 2008 (SCI-Expanded)
- XXIV. **Determination of birefringence dispersion in nematic liquid crystals by using an S-transform**
Ozder S., COŞKUN E., Koysal O., Kocahan O.
OPTICS LETTERS, vol.32, no.14, pp.2001-2003, 2007 (SCI-Expanded)
- XXV. **Optical phase distribution evaluation by using an S-transform**
Ozder S., KOCAHAN O., COŞKUN E., Goktas H.
OPTICS LETTERS, vol.32, no.6, pp.591-593, 2007 (SCI-Expanded)
- XXVI. **The effect of thermal annealing on impurity states in ferroelectric-semiconductor TlGaSe2 within the incommensurate phase**
Seyidov M., COŞKUN E., Sahin Y., Khamoev R., Suleymanov R.
SEMICONDUCTOR SCIENCE AND TECHNOLOGY, vol.21, no.2, pp.171-174, 2006 (SCI-Expanded)

Articles Published in Other Journals

- I. **An improved method for determination of refractive index of absorbing films: A simulation study**
Özcan S., Coşkun E., Kocahan Yılmaz Ö., Özder S.
AIP Conference Proceedings, vol.1815, pp.500091-500094, 2017 (Peer-Reviewed Journal)
- II. **An Improved Method For The Determination Of Birefringence Dispersion Of Liquid Crystal Cell: A Simulation Study**

Refereed Congress / Symposium Publications in Proceedings

- I. **Numerical Approach for Determination of The Refractive Index of Dielectric Film from Reflectance Spectrum at Various Angles of Incidence by Using Paul Wavelet**
SELAMET S., TİRYAKİ E., Emir C., COŞKUN E.
Türk Fizik Derneği 39. Kongresi (2023), Muğla, Turkey, 31 August - 04 September 2023, pp.128
- II. **Surface Profile Determination by Generalized Morse Wavelet: A Simulation Study**
UYANIK M., SELAMET S., KOCAHAN YILMAZ Ö., COŞKUN E.
Türk Fizik Derneği 38. Kongresi (2022), Muğla, Turkey, 31 August 2022
- III. **Determination of the theoretically created surface profile by Generalized S-Transform**
SELAMET S., KOCAHAN YILMAZ Ö., COŞKUN E.
Türk Fizik Derneği 38. Kongresi (2022), Muğla, Turkey, 31 August 2022
- IV. **Cardiac tissue models to investigate the heart mechanobiology**
Zanetti M., Andolfi L., Guttner E. B., COŞKUN E., BEK A., Taylor M. R., Mestroni L., Lazzarino M.
Crossnano Workshop 2022, Italy, 22 February 2022
- V. **TEMPERATURE DEPENDENT CHARACTERIZATION OF SnS/Si NANOWIRE DEVICE APPLICATION**
COŞKUN E., GÜLLÜ H. H., EMİR C., PARLAK M.
Turk Fizik Derneği 36 sempozyum, İstanbul, Turkey, 01 September 2020, pp.78
- VI. **Determination of surface profile of thin films by continuous wavelet transform.**
TİRYAKİ E., KOCAHAN YILMAZ Ö., COŞKUN E., ÖZDER S.
6. International Conference of Material Science and Nanotechnology for Next Generation (MSNG2019), Kayseri, Turkey, 16 - 17 October 2019
- VII. **Electrical Properties of ZnSe/Si Nanowire and ZnSe/Si Heterostructures**
BOZDOĞAN E., COŞKUN E., ÖZDER S., GÜLLÜ H. H., PARLAK M.
Turkish Physical Society 34th International Physics Congress (TFD-34), Muğla, Turkey, 5 - 09 September 2018
- VIII. **n-ZnSe/p-Si Nanotel Heteroeklemlerin Foto-İletkenlik Davranışlarının İncelenmesi**
COŞKUN E., GÜLLÜ H. H., PARLAK M.
23. Yoğun Madde Fiziği Ankara Toplantısı, Ankara, Turkey, 22 December 2017
- IX. **Determination of the Interface Properties of p-CZTSe/n-Si Nanowire Heterojunction Diode**
BAYRAKLI Ö., TERLEMEZOĞLU M., GÜLLÜ H. H., YILDIZ D. E., ÇOLAKOĞLU T., COŞKUN E., PARLAK M.
Materials Research Society (MRS) 2017 Fall Meeting, Boston, 26 November - 01 December 2017
- X. **Optical properties of silicon nanowires for different length fabricated by metal assisted chemical etching method**
BOZDOĞAN E., COŞKUN E., ÖZDER S., KOCAHAN YILMAZ Ö.
Turkish Physical Society 33th International Physics Congress, 6 - 09 September 2017
- XI. **Production of silicon nanowire having different size by using metal assisted chemical etching method**
BOZDOĞAN E., COŞKUN E., ÖZDER S., KOCAHAN YILMAZ Ö.
Turkish Physical Society 33th International Physics Congress, 6 - 09 September 2017
- XII. **Synthesis and Structural Characterization on the (Cu,Ag)GaTe₂ Thin Films Deposited on Si Nanowires**
COŞKUN E., GÜLLÜ H. H., BAYRAKLI Ö., TERLEMEZOĞLU M., PARLAK M.
European Materials Research Society-Spring Meeting 2017, 22 - 26 May 2017
- XIII. **A Simulation Study for Determination of Refractive Index Dispersion of Dielectric Film from Reflectance Spectrum by Using Paul Wavelet**
Tiryaki E., COŞKUN E., KOCAHAN YILMAZ Ö., ÖZDER S.
32nd International Physics Congress of Turkish-Physical-Society (TPS), Bodrum, Turkey, 6 - 09 September 2016,

- XIV. **Optical Phase Distribution Evaluation by Using Zero Order Generalized Morse Wavelet**
KOCAHAN YILMAZ Ö., Elmas M. N., Durmus C., COŞKUN E., Tiryaki E., ÖZDER S.
32nd International Physics Congress of Turkish-Physical-Society (TPS), Bodrum, Turkey, 6 - 09 September 2016,
vol.1815
- XV. **Quantitative Phase Imaging of Red Blood Cell by Diffraction Phase Microscopy**
KOCAHAN YILMAZ Ö., Tiryaki E., Durmus C., Elmas M. N., COŞKUN E., ÖZDER S.
International Workshop on Computing and Electromagnetics (CEM), Barcelona, Spain, 21 - 24 June 2017, pp.21-22
- XVI. **An Improved Method For Determination Of Refractive Index Of Absorbing Films: A Simulation Study**
Özcan S., Coşkun E., Kocahan Yılmaz Ö., Özder S.
32nd International Physics Congress of Turkish-Physical-Society (TPS), Bodrum, Turkey, 6 - 09 September 2016,
vol.1815
- XVII. **3D Profile Measurements of Objects by Using Zero Order Generalized Morse Wavelet**
KOCAHAN YILMAZ Ö., Durmus C., Elmas M. N., COŞKUN E., Tiryaki E., ÖZDER S.
32nd International Physics Congress of Turkish-Physical-Society (TPS), Bodrum, Turkey, 6 - 09 September 2016,
vol.1815
- XVIII. **An Improved Method For Simultaneous Determination Of Refractive Index And Thickness Of Dielectric Films A Simulation Study**
ÖZCAN S., COŞKUN E., KOCAHAN YILMAZ Ö., ÖZDER S.
Science and Applications of Thin Films, Congress & Exhibition - SATF 2016, İzmir, Turkey, 19 - 23 September 2016
- XIX. **Design and Device Application of Si Based Cu Ag Ga Te Thin Film Heterojunction**
GÜLLÜ H. H., COŞKUN E., BAYRAKLI Ö., PARLAK M.
Science and Application of Thin Films, Conference and Exhibition, 19 - 23 September 2016
- XX. **Determination of the Refractive Index of Dielectric Films from the Transmittance Spectrum by Using Morse Wavelet**
TİRYAKİ E., KOCAHAN YILMAZ Ö., COŞKUN E., ELMAS M. N., ÖZDER S.
Science and Applications of Thin Films, Conference & Exhibition SATF 2016, 19 - 23 September 2016
- XXI. **Theoretical Determination of the Refractive Index and Extinction Coefficient of an Absorbing Thin Film by Using Morse Wavelet**
TİRYAKİ E., KOCAHAN YILMAZ Ö., COŞKUN E., DURMUŞ Ç., ÖZDER S.
Science and Applications of Thin Films, Conference & Exhibition (SATF 2016), 19 - 23 September 2016
- XXII. **3D profile measurements of objects by using zero order generalized Morse wavelet**
KOCAHAN YILMAZ Ö., DURMUŞ Ç., ELMAS M. N., COŞKUN E., TİRYAKİ E., ÖZDER S.
Turkish Physical Society 32th International Physics Congress, 6 - 09 September 2016
- XXIII. **A simulation study for determination of refractive index dispersion of dielectric film from reflectance spectrum by using Paul wavelet**
TİRYAKİ E., COŞKUN E., ÖZDER S., BOZDOĞAN E., KOCAHAN YILMAZ Ö., ELMAS M. N.
Turkish Physical Society 32th International Physics Congress, 6 - 09 September 2016
- XXIV. **Determination of the refractive index dispersion of dielectric film from reflectance spectrum by using Morlet wavelet**
TİRYAKİ E., COŞKUN E., ÖZDER S., KUŞ E., KOCAHAN YILMAZ Ö., DURMUŞ Ç.
Turkish Physical Society 32th International Physics Congress, 6 - 09 September 2016
- XXV. **An improved method for determination of refractive index of absorbing films a simulation study**
ÖZCAN S., COŞKUN E., ÖZDER S., KOCAHAN YILMAZ Ö.
Turkish Physical Society 32th International Physics Congress, 6 - 09 September 2016
- XXVI. **Optical phase distribution evaluation by using zero order generalized Morse wavelet**
KOCAHAN YILMAZ Ö., ELMAS M. N., DURMUŞ Ç., COŞKUN E., TİRYAKİ E., ÖZDER S.
Turkish Physical Society 32th International Physics Congress, 6 - 09 September 2016
- XXVII. **Fabrication and Characterization of p CuInSe₂ n Si Heterojunction Diodes**
GÜLLÜ H. H., BAYRAKLI Ö., COŞKUN E., PARLAK M.
32nd European Photovoltaic Solar Energy Conference and Exhibition, 20 - 24 June 2016

- XXVIII. **Characterization of CZTSe Thin Films for Solar Cell**
BAYRAKLI Ö., GÜLLÜ H. H., TERLEMEZOĞLU M., PARLAK M., COŞKUN E.
32nd European Photovoltaic Solar Energy Conference and Exhibition, 20 - 24 June 2016
- XXIX. **Effect of Nanowire Length on Device Performance of n ZnSe p Si Nanowire Heterojunctions**
COŞKUN E., GÜLLÜ H. H., ÇOLAKOĞLU T., BAYRAKLI Ö., PARLAK M.
32nd European Photovoltaic Solar Energy Conference and Exhibition, 20 - 24 June 2016
- XXX. **Device characterization of Zn Sn Se ZTSe thin films for solar cell**
BAYRAKLI Ö., GÜLLÜ H. H., COŞKUN E., PARLAK M.
European Materials Research Society 2016, 2 - 06 May 2016
- XXXI. **Effect of nanowire length on device performance of n In₂Se₃ p Si heterojunctions**
COŞKUN E., ÇOLAKOĞLU T., GÜLLÜ H. H., BAYRAKLI Ö., PARLAK M.
European Materials Research Society 2016, 2 - 06 May 2016
- XXXII. **Studies on Device Properties of n ZnSe p Si Heterojunction Diode**
GÜLLÜ H. H., BAYRAKLI Ö., COŞKUN E., PARLAK M.
European Materials Research Society 2016, 2 - 06 May 2016
- XXXIII. **Optical Behaviour of Sequential Thermal Evaporation ZnInSe₂ Thin Films**
GÜLLÜ H. H., COŞKUN E., BAYRAKLI Ö., PARLAK M.
European Materials Research Society 2016, 2 - 06 May 2016
- XXXIV. **Device characterization of Cu Ag Ga Te thin films for photovoltaic applications**
COŞKUN E., GÜLLÜ H. H., PARLAK M.
Materials Research Society 2016, 28 March - 01 April 2016
- XXXV. **An Improved Method For The Determination Of Birefringence Dispersion Of Liquid Crystal Cell: A Simulation Study**
ÖZCAN S., COŞKUN E., KOCAHAN YILMAZ Ö., ÖZDER S.
9th International Physics Conference of the Balkan-Physical-Union (BPU), İstanbul, Turkey, 24 - 27 August 2015, vol.1722
- XXXVI. **Investigation of Electrical Properties of Cu Ag In Se Thin Films Deposited by Thermally Evaporation Method**
GÜLLÜ H. H., COŞKUN E., BAYRAKLI Ö., PARLAK M., ERÇELEBİ A. Ç.
EU PVSEC 2015 31st European Photovoltaic Solar Energy Conference and Exhibition, 14 - 18 September 2015
- XXXVII. **Fabrication and Characterization of p AgGaIn_{1-x}Te₂ n ZnInSe₂ Heterojunctions for Solar Cell Applications**
BAYRAKLI Ö., GÜLLÜ H. H., COŞKUN E., PARLAK M.
2015 MRS Spring Meeting & Exhibit, 6 - 10 April 2015
- XXXVIII. **Material and Device Characterization of Cu_{0.5}Ag_{0.5}InSe₂ and ZnInSe₂ Thin Films for Photovoltaic Applications**
GÜLLÜ H. H., COŞKUN E., BAYRAKLI Ö., PARLAK M.
2015 MRS Spring Meeting & Exhibit, 6 - 10 April 2015
- XXXIX. **Investigation of optical parameters of thermally evaporated ZnSe thin films**
Güllü H. H., COŞKUN E., Parlak M.
3rd Turkish Solar Electricity Conference and Exhibition (SolarTR), Ankara, Turkey, 27 - 29 April 2015, vol.12, pp.1224-1228
- XL. **Characterization of Sputtered Cu Zn Sn Te Thin Films for Device Applications**
Hosseini A., GÜLLÜ H. H., COŞKUN E., TURAN R., ERÇELEBİ A. Ç.
E-MRS 2014, 03 June 2014
- XLI. **Fabrication and Characterization of TiO₂Thin Films for Device Applications**
HOSSEINI A., GÜLLÜ H. H., COŞKUN E., TURAN R., ERÇELEBİ A. Ç.
E-MRS 2014, 20 - 22 April 2014
- XLII. **PLAZMA DESTEKLİ KİMYASAL BUHAR BİRİKTİRME SİSTEMİ İLE BÜYÜTÜLEN HİDROJENLENMİŞ AMORF SİLİSYUM KARBÜR İNCE FİMLERE RADYO FREKANSI GÜCÜ ETKİSİNİN X ISINI FOTOELEKTRON SPEKTROMETRESİ İLE İNCELENMESİ**

GÜLLÜ H. H., COŞKUN E., PARLAK M.

MYOMAT 2009: IULUSAL METAL, YARIĐLETKEN veOKSĐT MATERYALLERĐN ÜRETĐMĐNDEKULLANILAN SĐSTEMLER ve ANALİZ TEKNİKLERİ KONGRESİ, Turkey, 20 - 22 April 2008

XLIII. Profile Measurement of Objects by Using Stockwell and Continuous Wavelet Transforms

Kocahan O., COŞKUN E., ÖZDER S.

IEEE 16th Signal Processing and Communications Applications Conference, Aydın, Turkey, 20 - 22 April 2008, pp.804-807

XLIV. S-transform analysis of projected fringe patterns - art. no. 66161A

Kocahan O., ÖZDER S., COŞKUN E.

Conference on Optical Measurement Systems for Industrial Inspection V, Munich, Germany, 18 - 22 June 2007, vol.6616

XLV. Optical phase distribution evaluation by using S-transform

Kocallan O., ÖZDER S., COŞKUN E.

6th International Conference of the Balkan-Physical-Union, İstanbul, Turkey, 22 - 26 August 2006, vol.899, pp.684

XLVI. The determination of birefringence dispersion in nematic liquid crystals by using the S-transform

COŞKUN E., Oezder S., Kocahan O., Koeysal O.

6th International Conference of the Balkan-Physical-Union, İstanbul, Turkey, 22 - 26 August 2006, vol.899, pp.439-440

Supported Projects

2021 - 2023	Development of surface profile measurement algorithm for the determination of 3D surface profiles of thin films, TUBITAK Project
2019 - 2020	Metal destekli kimyasal aşındırma yöntemi ile farklı boyutlarda veveya açılarda Silisyum nano ipliksi yapıların üretimi, Project Supported by Higher Education Institutions
2018 - 2020	Advanced Heterojunction Si Solar Cells with SiC and Metal Oxides Thin Films (SiMOX), TÜBİTAK International Bilateral Joint Cooperation Program Project
2018 - 2019	Imaging the surfaces of thin films by white light phase microscopy and calculating the phase distributions using the generalized stockwell transform, Project Supported by Higher Education Institutions
2015 - 2018	Generalized Morse Wavelet Phase Method for the Determination of 3D Surface Profile of Micrometer-size Samples , TUBITAK Project
2010 - 2012	İnce Filmlerin Optik Özelliklerinin İntegral Dönüşüm Yöntemleri İle Belirlenmesi, Project Supported by Higher Education Institutions

Scientific Refereeing

March 2010	Optics Letters, SCI Journal
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Metrics

Publication: 75
Citation (WoS): 163
Citation (Scopus): 174
H-Index (WoS): 7
H-Index (Scopus): 7

Scholarships

